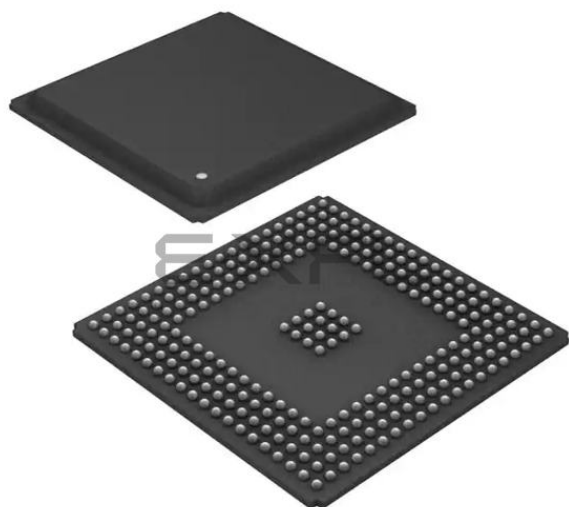




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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	2560
Number of I/O	202
Number of Gates	54000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	272-BBGA
Supplier Device Package	272-PBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx36-bg272i

2.4 Plastic Device Resources

Table 2 • Plastic Device Resources

Device	User I/Os											
	PLCC 44-Pin	PLCC 68-Pin	PLCC 84-Pin	PQFP 100-Pin	PQFP 144- Pin	PQFP 160-Pin	PQFP 208- Pin	PQFP 240-Pin	VQFP 80-Pin	VQFP 100- Pin	TQFP 176- Pin	PBGA 272- Pin
A40MX02	34	57	–	57	–	–	–	–	57	–	–	–
A40MX04	34	57	69	69	–	–	–	–	69	–	–	–
A42MX09	–	–	72	83	95	101	–	–	–	83	104	–
A42MX16	–	–	72	83	–	125	140	–	–	83	140	–
A42MX24	–	–	72	–	–	125	176	–	–	–	150	–
A42MX36	–	–	–	–	–	–	176	202	–	–	–	202

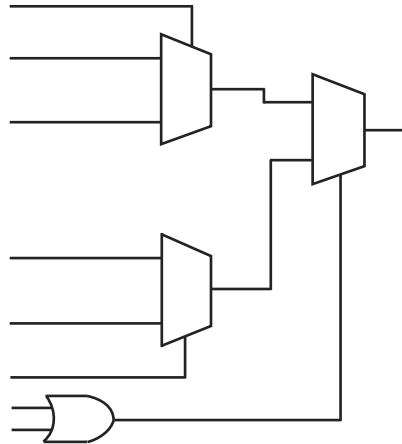
Note: Package Definitions: PLCC = Plastic Leaded Chip Carrier, PQFP = Plastic Quad Flat Pack, TQFP = Thin Quad Flat Pack, VQFP = Very Thin Quad Flat Pack, PBGA = Plastic Ball Grid Array

2.5 Ceramic Device Resources

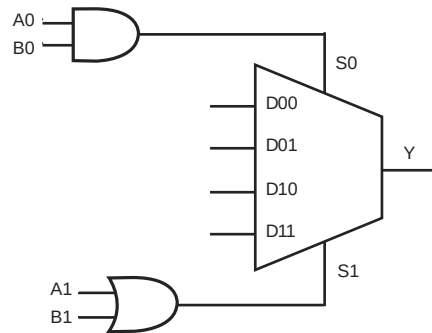
Table 3 • Ceramic Device Resources

Device	User I/Os			
	CPGA 132-Pin	CQFP 172-Pin	CQFP 208-Pin	CQFP 256-Pin
A42MX09	95			
A42MX16		131		
A42MX36			176	202

Note: Package Definitions: CQFP = Ceramic Quad Flat Pack

Figure 2 • 42MX C-Module Implementation

The 42MX devices contain three types of logic modules: combinatorial (C-modules), sequential (S-modules) and decode (D-modules). The following figure illustrates the combinatorial logic module. The S-module, shown in Figure 4, page 8, implements the same combinatorial logic function as the C-module while adding a sequential element. The sequential element can be configured as either a D-flip-flop or a transparent latch. The S-module register can be bypassed so that it implements purely combinatorial logic.

Figure 3 • 42MX C-Module Implementation

Additionally, the back-annotation flow is compatible with all the major simulators and the simulation results can be cross-probed with Silicon Explorer II, Microsemi's integrated verification and logic analysis tool. Another tool included in the Libero software is the SmartGen macro builder, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design.

Microsemi's Libero software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synopsys, and Cadence design systems.

See the Libero IDE web content at www.microsemi.com/soc/products/software/libero/default.aspx for further information on licensing and current operating system support.

3.6 Related Documents

The following sections give the list of related documents which can be referred for this datasheet.

3.6.1 Application Notes

- *AC278: BSDL Files Format Description*
- *AC225: Programming Antifuse Devices*
- *AC168: Implementation of Security in Microsemi Antifuse FPGAs*

3.6.2 User Guides and Manuals

- *Antifuse Macro Library Guide*
- *Silicon Sculptor Programmers User Guide*

3.6.3 Miscellaneous

Libero IDE Flow Diagram

3.7 5.0 V Operating Conditions

The following tables show 5.0 V operating conditions.

Table 12 • Absolute Maximum Ratings for 40MX Devices*

Symbol	Parameter	Limits	Units
VCC	DC Supply Voltage	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCC+0.5	V
VO	Output Voltage	–0.5 to VCC+0.5	V
t _{STG}	Storage Temperature	–65 to +150	°C

Note: *Stresses beyond those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the recommended operating conditions.

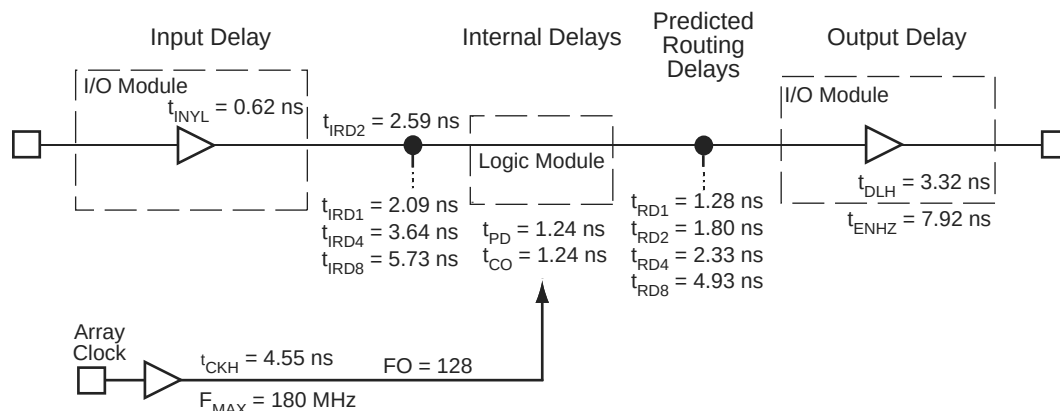
Table 13 • Absolute Maximum Ratings for 42MX Devices*

Symbol	Parameter	Limits	Units
VCCI	DC Supply Voltage for I/Os	–0.5 to +7.0	V
VCCA	DC Supply Voltage for Array	–0.5 to +7.0	V
VI	Input Voltage	–0.5 to VCCI+0.5	V
VO	Output Voltage	–0.5 to VCCI+0.5	V
t _{STG}	Storage Temperature	–65 to +150	°C

3.10 Timing Models

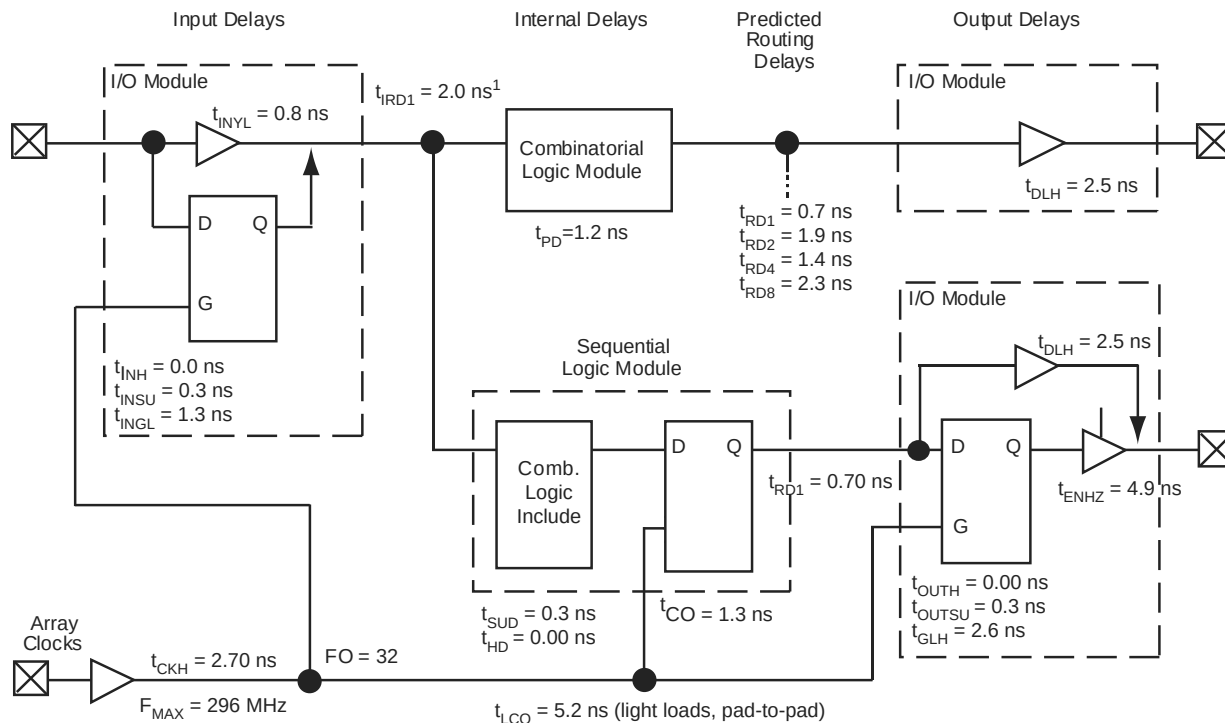
The following figures show various timing models.

Figure 17 • 40MX Timing Model*



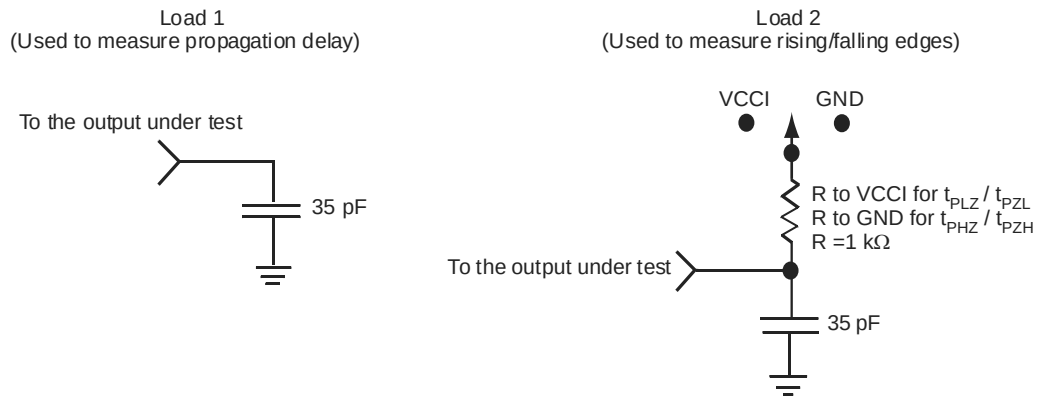
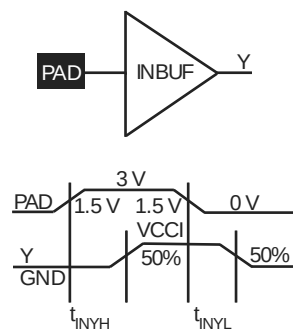
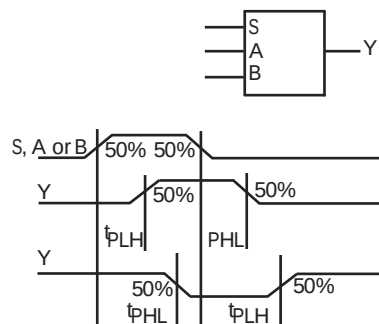
Note: Values are shown for 40MX –3 speed devices at 5.0 V worst-case commercial conditions.

Figure 18 • 42MX Timing Model



Note: 1. Input module predicted routing delay

Note: 2. Values are shown for A42MX09 –3 at 5.0 V worst-case commercial conditions.

Figure 22 • AC Test Loads**Figure 23 • Input Buffer Delays****Figure 24 • Module Delays**

approximately a 3 ns to a 6 ns delay, which is represented statistically in higher fanout (FO=8) routing delays in the data sheet specifications section, shown in Table 34, page 41.

3.11.3 Timing Derating

MX devices are manufactured with a CMOS process. Therefore, device performance varies according to temperature, voltage, and process changes. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature and worst-case processing.

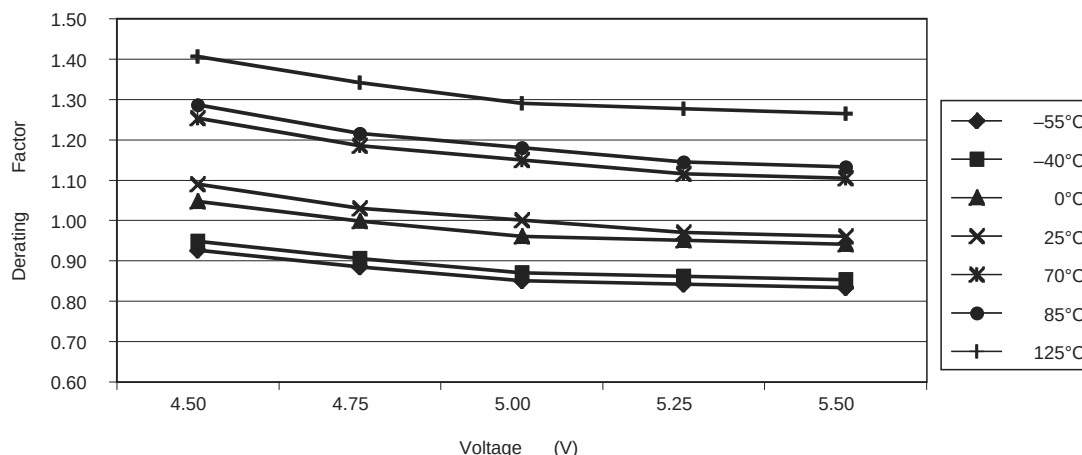
3.11.4 Temperature and Voltage Derating Factors

The following tables and figures show temperature and voltage derating factors for 40MX and 42MX FPGAs.

Table 28 • 42MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 5.0\text{ V}$)

42MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
4.50	0.93	0.95	1.05	1.09	1.25	1.29	1.41
4.75	0.88	0.90	1.00	1.03	1.18	1.22	1.34
5.00	0.85	0.87	0.96	1.00	1.15	1.18	1.29
5.25	0.84	0.86	0.95	0.97	1.12	1.14	1.28
5.50	0.83	0.85	0.94	0.96	1.10	1.13	1.26

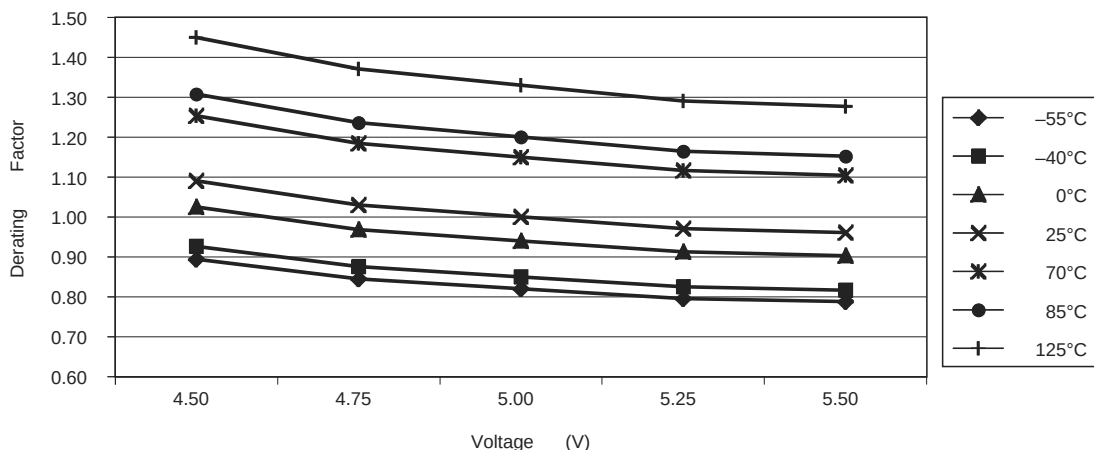
Figure 34 • 42MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 5.0\text{ V}$)



Note: This derating factor applies to all routing and propagation delays

Table 29 • 40MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 5.0\text{ V}$)

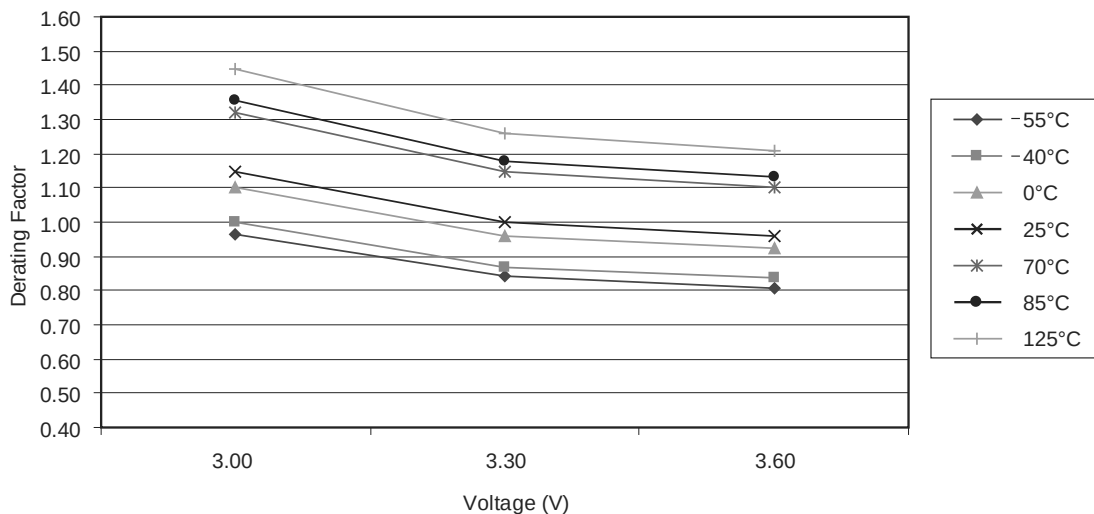
40MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
4.50	0.89	0.93	1.02	1.09	1.25	1.31	1.45
4.75	0.84	0.88	0.97	1.03	1.18	1.24	1.37
5.00	0.82	0.85	0.94	1.00	1.15	1.20	1.33
5.25	0.80	0.82	0.91	0.97	1.12	1.16	1.29
5.50	0.79	0.82	0.90	0.96	1.10	1.15	1.28

Figure 35 • 40MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 5.0\text{ V}$)

Note: This derating factor applies to all routing and propagation delays

Table 30 • 42MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 3.3\text{ V}$)

42MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
3.00	0.97	1.00	1.10	1.15	1.32	1.36	1.45
3.30	0.84	0.87	0.96	1.00	1.15	1.18	1.26
3.60	0.81	0.84	0.92	0.96	1.10	1.13	1.21

Figure 36 • 42MX Junction Temperature and Voltage Derating Curves (Normalized to $T_J = 25^\circ\text{C}$, $V_{CCA} = 3.3\text{ V}$)

Note: This derating factor applies to all routing and propagation delays

Table 31 • 40MX Temperature and Voltage Derating Factors (Normalized to $T_J = 25^\circ\text{C}$, $V_{CC} = 3.3\text{ V}$)

40MX Voltage	Temperature						
	-55°C	-40°C	0°C	25°C	70°C	85°C	125°C
3.00	1.08	1.12	1.21	1.26	1.50	1.64	2.00
3.30	0.86	0.89	0.96	1.00	1.19	1.30	1.59

Table 36 • A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ENLZ}	Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d _{TLH}	Delta LOW to HIGH		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{THL}	Delta HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

Table 37 • A40MX04 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.6		5.3		5.6		7.0		9.8		ns
t _A	Flip-Flop Clock Input Period	6.8		7.8		8.9		10.4		14.6		ns
f _{MAX}	Flip-Flop (Latch) Clock Frequency (FO = 128)		109		101		92		80		48	MHz
Input Module Propagation Delays												
t _{INYH}	Pad-to-Y HIGH		1.0		1.1		1.3		1.5		2.1	ns
t _{INYL}	Pad-to-Y LOW		0.9		1.0		1.1		1.3		1.9	ns

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description	–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ACO} Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		11.3		12.5		14.2		16.7		23.3	ns
d _{TLH} Capacitive Loading, LOW to HIGH		0.04		0.04		0.05		0.06		0.08	ns/pF
d _{THL} Capacitive Loading, HIGH to LOW		0.05		0.05		0.06		0.07		0.10	ns/pF

1. For dual-module macros use tPD1 + tRD1 + taped, to + tRD1 + taped, or tPD1 + tRD1 + tusk, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading.

Table 42 • A42MX24 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Logic Module Combinatorial Functions ¹												
t _{PD}	Internal Array Module Delay	1.2		1.3		1.5		1.8		2.5		ns
t _{PDD}	Internal Decode Module Delay	1.4		1.6		1.8		2.1		3.0		ns
Logic Module Predicted Routing Delays ²												
t _{RD1}	FO = 1 Routing Delay	0.8		0.9		1.0		1.2		1.7		ns
t _{RD2}	FO = 2 Routing Delay	1.0		1.2		1.3		1.5		2.1		ns
t _{RD3}	FO = 3 Routing Delay	1.3		1.4		1.6		1.9		2.6		ns
t _{RD4}	FO = 4 Routing Delay	1.5		1.7		1.9		2.2		3.1		ns
t _{RD5}	FO = 8 Routing Delay	2.4		2.7		3.0		3.6		5.0		ns
Logic Module Sequential Timing ^{3, 4}												
t _{CO}	Flip-Flop Clock-to-Output	1.3		1.4		1.6		1.9		2.7		ns
t _{GO}	Latch Gate-to-Output	1.2		1.3		1.5		1.8		2.5		ns
t _{SUD}	Flip-Flop (Latch) Set-Up Time	0.3		0.4		0.4		0.5		0.7		ns
t _{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t _{RO}	Flip-Flop (Latch) Reset-to-Output	1.4		1.6		1.8		2.1		2.9		ns
t _{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.4		0.5		0.5		0.6		0.8		ns
t _{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.7		4.2		4.9		6.9		ns
t _{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.4		4.8		5.3		6.5		9.0		ns

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description			–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		Units
			Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 635	0.0		0.0		0.0		0.0		0.0		ns
t _{HEXT}	Input Latch External Hold	FO = 32	2.8		3.2		3.6		4.2		5.9		ns
		FO = 635	3.3		3.7		4.2		4.9		6.9		ns
t _P	Minimum Period (1/f _{MAX})	FO = 32	5.5		6.1		6.6		7.6		12.7		ns
		FO = 635	6.0		6.6		7.2		8.3		13.8		ns
f _{MAX}	Maximum Datapath Frequency	FO = 32		180		164		151		131		79	MHz
		FO = 635		166		151		139		121		73	MHz
TTL Output Module Timing ⁵													
t _{DLH}	Data-to-Pad HIGH			2.6		2.8		3.2		3.8		5.3	ns
t _{DHL}	Data-to-Pad LOW			3.0		3.3		3.7		4.4		6.2	ns
t _{ENZH}	Enable Pad Z to HIGH			2.7		3.0		3.3		3.9		5.5	ns
t _{ENZL}	Enable Pad Z to LOW			3.0		3.3		3.7		4.3		6.1	ns
t _{ENHZ}	Enable Pad HIGH to Z			5.3		5.8		6.6		7.8		10.9	ns

Input, output, tristate or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/Os pins are configured by the Designer software as shown in Table 46, page 84.

Table 46 • Configuration of Unused I/Os

Device	Configuration
A40MX02, A40MX04	Pulled LOW
A42MX09, A42MX16	Pulled LOW
A42MX24, A42MX36	Tristated

In all cases, it is recommended to tie all unused MX I/O pins to LOW on the board. This applies to all dual-purpose pins when configured as I/Os as well.

LP, Low Power Mode

Controls the low power mode of all 42MX devices. The device is placed in the low power mode by connecting the LP pin to logic HIGH. In low power mode, all I/Os are tristated, all input buffers are turned OFF, and the core of the device is turned OFF. To exit the low power mode, the LP pin must be set LOW. The device enters the low power mode 800 ns after the LP pin is driven to a logic HIGH. It will resume normal operation in 200 μ s after the LP pin is driven to a logic LOW.

MODE, Mode

Controls the use of multifunction pins (DCLK, PRA, PRB, SDI, TDO). The MODE pin is held HIGH to provide verification capability. The MODE pin should be terminated to GND through a 10k Ω resistor so that the MODE pin can be pulled HIGH when required.

NC, No Connection

This pin is not connected to circuitry within the device. These pins can be driven to any voltage or can be left floating with no effect on the operation of the device.

PRA, I/O

PRB, I/OProbe A/B

The Probe pin is used to output data from any user-defined design node within the device. Each diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. The Probe pin is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

QCLKA/B/C/D, I/O Quadrant Clock

Quadrant clock inputs for A42MX36 devices. When not used as a register control signal, these pins can function as user I/Os.

SDI, I/O Serial Data Input

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

SDO, I/O Serial Data Output

Serial data output for diagnostic probe and device programming. SDO is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW. SDO is available for 42MX devices only.

When Silicon Explorer II is being used, SDO will act as an output while the "checksum" command is run. It will return to user I/O when "checksum" is complete.

TCK, I/O Test Clock

Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDI, I/O Test Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDO, I/O Test Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TMS, I/O Test Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a 10k Ω pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

VCC, Supply Voltage

Input supply voltage for 40MX devices

VCCA, Supply Voltage

Supply voltage for array in 42MX devices

VCCI, Supply Voltage

Supply voltage for I/Os in 42MX devices

WD, I/O Wide Decode Output

When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.

Table 49 • PL84

PL84				
Pin Number	A40MX04 Function	A42MX09 Function	A42MX16 Function	A42MX24 Function
47	I/O	I/O	I/O	WD, I/O
48	I/O	I/O	I/O	I/O
49	I/O	GND	GND	GND
50	I/O	I/O	I/O	WD, I/O
51	I/O	I/O	I/O	WD, I/O
52	I/O	SDO, I/O	SDO, I/O	SDO, TDO, I/O
53	I/O	I/O	I/O	I/O
54	I/O	I/O	I/O	I/O
55	I/O	I/O	I/O	I/O
56	I/O	I/O	I/O	I/O
57	I/O	I/O	I/O	I/O
58	I/O	I/O	I/O	I/O
59	I/O	I/O	I/O	I/O
60	GND	I/O	I/O	I/O
61	GND	I/O	I/O	I/O
62	I/O	I/O	I/O	TCK, I/O
63	I/O	LP	LP	LP
64	CLK, I/O	VCCA	VCCA	VCCA
65	I/O	VCCI	VCCI	VCCI
66	MODE	I/O	I/O	I/O
67	VCC	I/O	I/O	I/O
68	VCC	I/O	I/O	I/O
69	I/O	I/O	I/O	I/O
70	I/O	GND	GND	GND
71	I/O	I/O	I/O	I/O
72	SDI, I/O	I/O	I/O	I/O
73	DCLK, I/O	I/O	I/O	I/O
74	PRA, I/O	I/O	I/O	I/O
75	PRB, I/O	I/O	I/O	I/O
76	I/O	SDI, I/O	SDI, I/O	SDI, I/O
77	I/O	I/O	I/O	I/O
78	I/O	I/O	I/O	WD, I/O
79	I/O	I/O	I/O	WD, I/O
80	I/O	I/O	I/O	WD, I/O
81	I/O	PRA, I/O	PRA, I/O	PRA, I/O
82	GND	I/O	I/O	I/O
83	I/O	CLKA, I/O	CLKA, I/O	CLKA, I/O

Figure 42 • PQ144

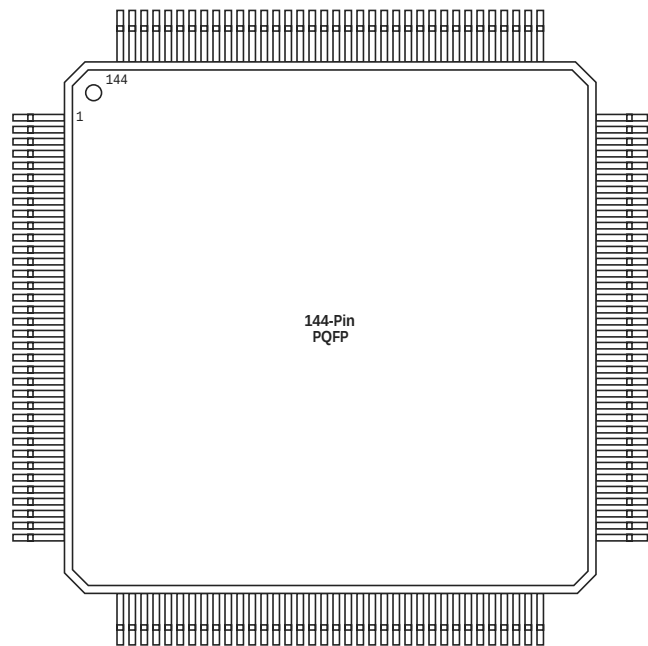


Table 51 • PQ144

PQ144	
Pin Number	A42MX09 Function
1	I/O
2	MODE
3	I/O
4	I/O
5	I/O

Figure 44 • PQ208

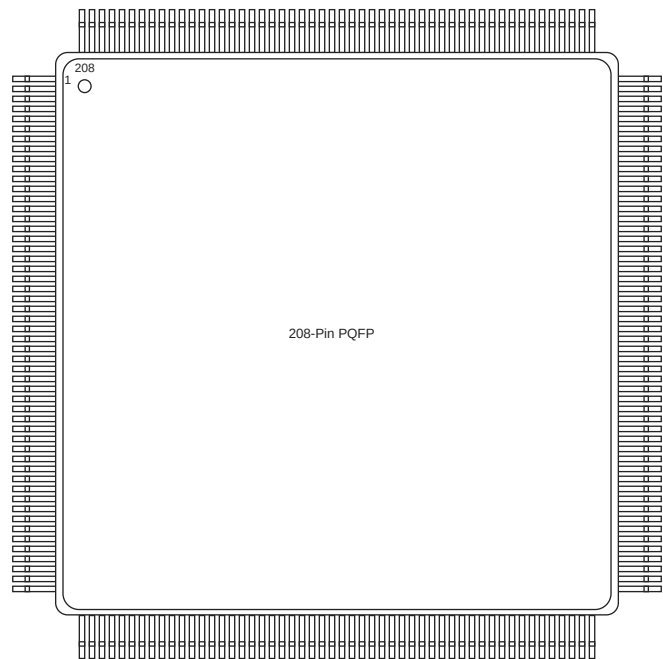


Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
1	GND	GND	GND
2	NC	VCCA	VCCA
3	MODE	MODE	MODE
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	NC	I/O	I/O
10	NC	I/O	I/O
11	NC	I/O	I/O
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	NC	I/O	I/O
17	VCCA	VCCA	VCCA
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	I/O	I/O	I/O

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
95	NC	I/O	I/O
96	NC	I/O	I/O
97	NC	I/O	I/O
98	VCCI	VCCI	VCCI
99	I/O	I/O	I/O
100	I/O	WD, I/O	WD, I/O
101	I/O	WD, I/O	WD, I/O
102	I/O	I/O	I/O
103	SDO, I/O	SDO, TDO, I/O	SDO, TDO, I/O
104	I/O	I/O	I/O
105	GND	GND	GND
106	NC	VCCA	VCCA
107	I/O	I/O	I/O
108	I/O	I/O	I/O
109	I/O	I/O	I/O
110	I/O	I/O	I/O
111	I/O	I/O	I/O
112	NC	I/O	I/O
113	NC	I/O	I/O
114	NC	I/O	I/O
115	NC	I/O	I/O
116	I/O	I/O	I/O
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O
121	I/O	I/O	I/O
122	I/O	I/O	I/O
123	I/O	I/O	I/O
124	I/O	I/O	I/O
125	I/O	I/O	I/O
126	GND	GND	GND
127	I/O	I/O	I/O
128	I/O	TCK, I/O	TCK, I/O
129	LP	LP	LP
130	VCCA	VCCA	VCCA
131	GND	GND	GND

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
15	QCLKC, I/O
16	I/O
17	WD, I/O
18	WD, I/O
19	I/O
20	I/O
21	WD, I/O
22	WD, I/O
23	I/O
24	PRB, I/O
25	I/O
26	CLKB, I/O
27	I/O
28	GND
29	VCCA
30	VCCI
31	I/O
32	CLKA, I/O
33	I/O
34	PRA, I/O
35	I/O
36	I/O
37	WD, I/O
38	WD, I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	QCLKD, I/O
46	I/O
47	WD, I/O
48	WD, I/O
49	I/O
50	I/O
51	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
52	VCCI
53	I/O
54	WD, I/O
55	WD, I/O
56	I/O
57	SDI, I/O
58	I/O
59	VCCA
60	GND
61	GND
62	I/O
63	I/O
64	I/O
65	I/O
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	VCCI
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	I/O
83	I/O
84	I/O
85	VCCA
86	I/O
87	I/O
88	VCCA

Table 60 • BG272

BG272	
Pin Number	A42MX36 Function
C3	GND
C4	I/O
C5	WD, I/O
C6	I/O
C7	QCLKC, I/O
C8	I/O
C9	I/O
C10	CLKB
C11	PRA, I/O
C12	WD, I/O
C13	I/O
C14	QCLKD, I/O
C15	I/O
C16	WD, I/O
C17	SDI, I/O
C18	I/O
C19	I/O
C20	I/O
D1	I/O
D2	I/O
D3	I/O
D4	I/O
D5	VCCI
D6	I/O
D7	I/O
D8	VCCA
D9	WD, I/O
D10	VCCI
D11	I/O
D12	VCCI
D13	I/O
D14	VCCI
D15	I/O
D16	VCCA
D17	GND
D18	I/O
D19	I/O